Green Journals

International Approved Journals

Journal Information

Journal Title	IEEE TRANSACTIONS ON ELECTRON DEVICES
Publisher	IEEE
ISSN	0018-9383
E-ISSN	1557-9646
Database	Clarivate
Domain	Physical Sciences

Classification History

Year	A+	A	B	C
2026		✓	✓	
2025		✓	✓	
2024		✓	✓	
2023		✓	✓	
2021/2022		✓	✓	
2020		✓	✓	
2019		✓	✓	
2018		✓		

Classification: The table above shows all journal classifications recorded for each classification year in the Green Journals database. A journal may have more than one classification in the same year.

Recent Articles

β -Ga ₂ O ₃ -Based Solar-Blind Ultraviolet Event-Based Sensor
2026-10 Vol. 73 Issue 10 Pages 6187-6192
Authors: Xiaobo She, Yifan Yu, Huixue Lu et al.
DOI: 10.1109/ted.2026.3728405

Implementation of Retina-Inspired Integrated Visual Functions Based on All-Solution-Processed Biomimetic Synaptic Transistors
2026-10 Vol. 73 Issue 10 Pages 6318-6324
Authors: Jingxue Zhao, Hainan Zhang, Haoran Wang et al.
DOI: 10.1109/ted.2026.3727407

Modeling Temperature Effects on MOS Capacitors in Charge Amplifier Feedback
2026-10 Vol. 73 Issue 10 Pages 6207-6214
Authors: Massimo Manghisoni, Luca Ghislotti, Paolo Lazzaroni et al.
DOI: 10.1109/ted.2026.3724517

MgO-Interface Ferromagnetic Layers for Robust Top Pinned Layer in Perpendicular Magnetic Tunnel Junctions
2026-10 Vol. 73 Issue 10 Pages 6070-6076
Authors: Shujun Ye, Koichi Nishioka
DOI: 10.1109/ted.2026.3722489

Performance Improvement by Carbon Content Modulation in SiN Spacer for NMOSFET
2026-10 Vol. 73 Issue 10 Pages 6113-6117
Authors: Ran Bi, Cheng-Hao Liang, Yu-Long Jiang
DOI: 10.1109/ted.2026.3721456

1700-V Enhancement-Mode MIS-HEMTs With Fully Recessed-Gate on 6-in GaN-on-Si Wafer
2026-10 Vol. 73 Issue 10 Pages 5936-5943
Authors: Yun Lei, Qingyuan Zuo, Nan Sun et al.
DOI: 10.1109/ted.2026.3726922

Electrical and Trap Characteristic Evolution of Bottom-Gated CNT FETs Under Positive and Negative Gate Bias Stress
2026-10 Vol. 73 Issue 10 Pages 6034-6039
Authors: Yushan Yao, Hui Zhu, Yang Yang et al.
DOI: 10.1109/ted.2026.3724507

Moderate Temperature Annealing to Release Residual Stress in MPCVD Diamond
2026-10 Vol. 73 Issue 10 Pages 6046-6054
Authors: Yunfei Wang, Yuhao Zhao, Hao Wang et al.
DOI: 10.1109/ted.2026.3721465

IEEE Transactions on Electron Devices Publication Information
2026-10 Vol. 73 Issue 10 Pages C2-C2
DOI: 10.1109/ted.2026.3731367

Suppressing Poole--Frenkel Instability in NbO _x Memristors Through an Ultrathin SiO _x Tunneling Layer
2026-10 Vol. 73 Issue 10 Pages 6282-6288
Authors: Zuyu Xu, Min Zhang, Wendong Lu et al.
DOI: 10.1109/ted.2026.3728400